Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/651,062	AOKI ET AL.	
Examiner	Art Unit	
Christopher M. Keehan	1712	

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SEARCHED			
Class	Subclass	Date	Examiner
428	447	3/28/2005	СМК
313	506		
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INTERFERENCE SEARCHED			
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	DATE	EXMR
EAST	3/28/2005	CMK
Inventor name search		
10/337307, 09/789748		